

# Lecture 6 – 16/10/2024

## Occupancy statistics and band filling

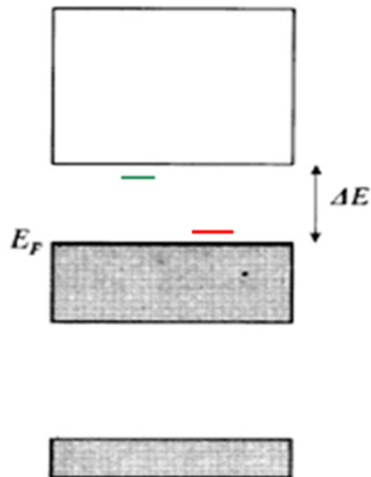
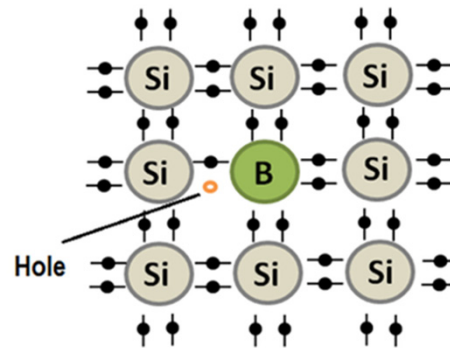
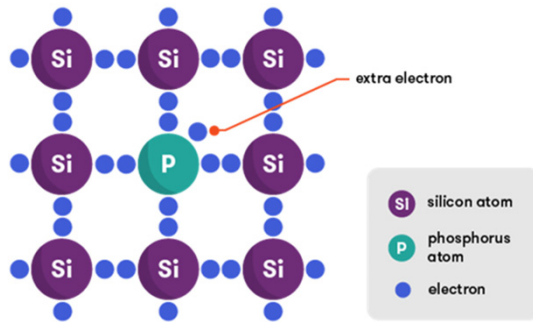
- Semiconductors: non-degenerate, intrinsic, degenerate, doped
- Occupancy of donor and acceptor levels
- Charge neutrality condition
- Doped semiconductors – temperature dependence

## Carrier transport

- Mobility at moderate electric field

# Summary of Lecture 5: donors and acceptors

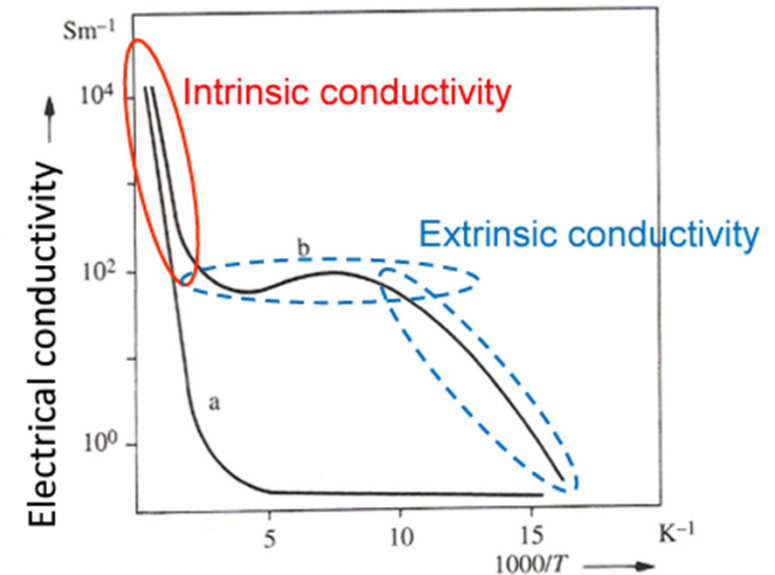
n-type material



$$E_n = -13.6 \text{ eV} \times \frac{m^*}{\epsilon_r^2 m_0 n^2}$$

Counts if shallow acceptors or donors  
Breaks down at high concentration –  
Band tailing effect

| Semiconductors | P  | As   | Sb  | Bi |
|----------------|----|------|-----|----|
| Ge             | 12 | 12.7 | 9.6 |    |
| Si             | 44 | 49   | 39  | 69 |

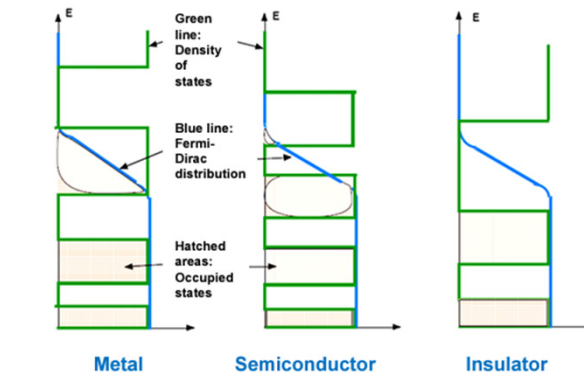
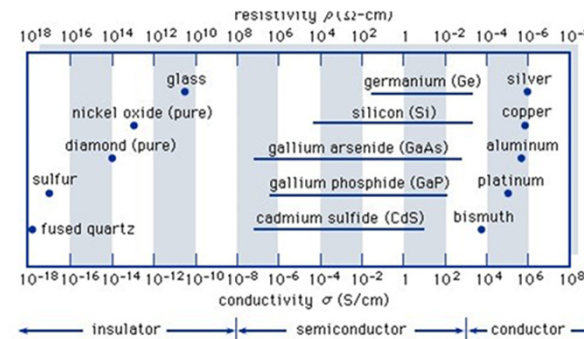
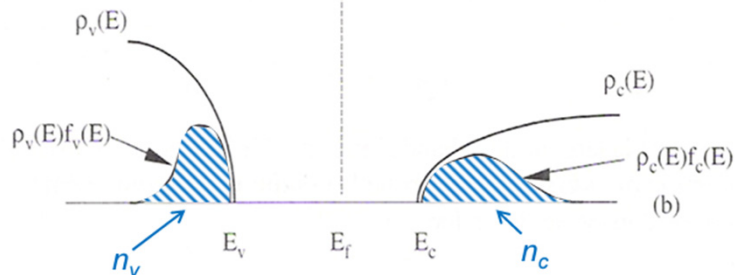
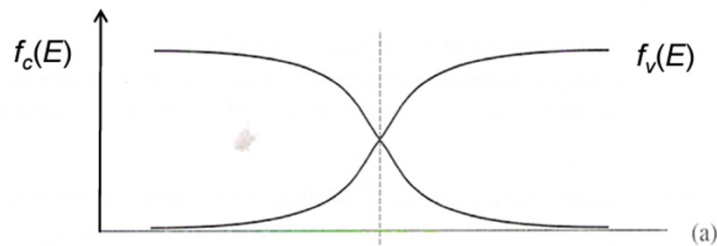


# Summary of Lecture 5: density of states and band filling

$$\rho_{3D}(E) = \frac{dN_{3D}(E)}{dE} = \frac{1}{2\pi^2} \left( \frac{2m^*}{\hbar^2} \right)^{3/2} \sqrt{E - E_0}$$

$$f(E) = \frac{1}{1 + e^{(E - E_F)/k_B T}}$$

$$n_c = \int_{E_c}^{+\infty} \rho_c(E) f_c(E) dE$$



$$n = N_c e^{-(E_c - E_F)/k_B T}$$

$$p = N_v e^{-(E_F - E_v)/k_B T}$$

|      | $N_c (10^{19} \text{ cm}^{-3})$ | $N_v (10^{19} \text{ cm}^{-3})$ |
|------|---------------------------------|---------------------------------|
| Si   | 2.8                             | 1.0                             |
| Ge   | 1                               | 0.4                             |
| GaAs | 0.04                            | 1.2                             |

# Fermi level calculation

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$$n = N_c e^{(E_F - E_c)/k_B T}$$

$$p = N_v e^{(E_v - E_F)/k_B T}$$

*Remark:  $n$  and  $p$  can be experimentally measured (Hall effect, electrochemical C-V profiling)*

$$E_F = E_c - k_B T \ln \frac{N_c}{n} = E_v + k_B T \ln \frac{N_v}{p}$$

- When  $n$  (or  $p$ )  $\ll N_c$  (or  $N_v$ )  $\Rightarrow E_F$  lies in the bandgap
- When  $n$  (or  $p$ )  $> N_c$  (or  $N_v$ )  $\Rightarrow$  the Fermi level lies within the CB (or VB)  
 $\Rightarrow$  **The semiconductor is then said to be *degenerate***

# Thermodynamic equilibrium

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At equilibrium  $\Rightarrow$  same chemical potential, i.e., same  $E_F$ , across the sample whatever the semiconducting structure (which remains true for an unbiased device whatever its complexity)



The  $np$  product for a non-degenerate semiconductor is then independent of the Fermi level position and is given by:

$$np = N_c N_v e^{-\frac{E_c - E_v}{k_B T}} = N_c N_v e^{-\frac{E_g}{k_B T}}$$

Product that depends on  $m^{*3/2}$ ,  $T^{3/2}$ , and  $E_g$

For a given semiconductor,  **$np$  is a function of temperature**. This is a **mass action law**, which expresses the thermodynamic equilibrium condition for electrons and holes.

# Intrinsic semiconductors

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A pure and perfect semiconductor is **intrinsic**

The origin of carriers present in the CB and VB is endogenous, i.e., free carriers are only due to the thermal activation process of electrons from the VB to the CB

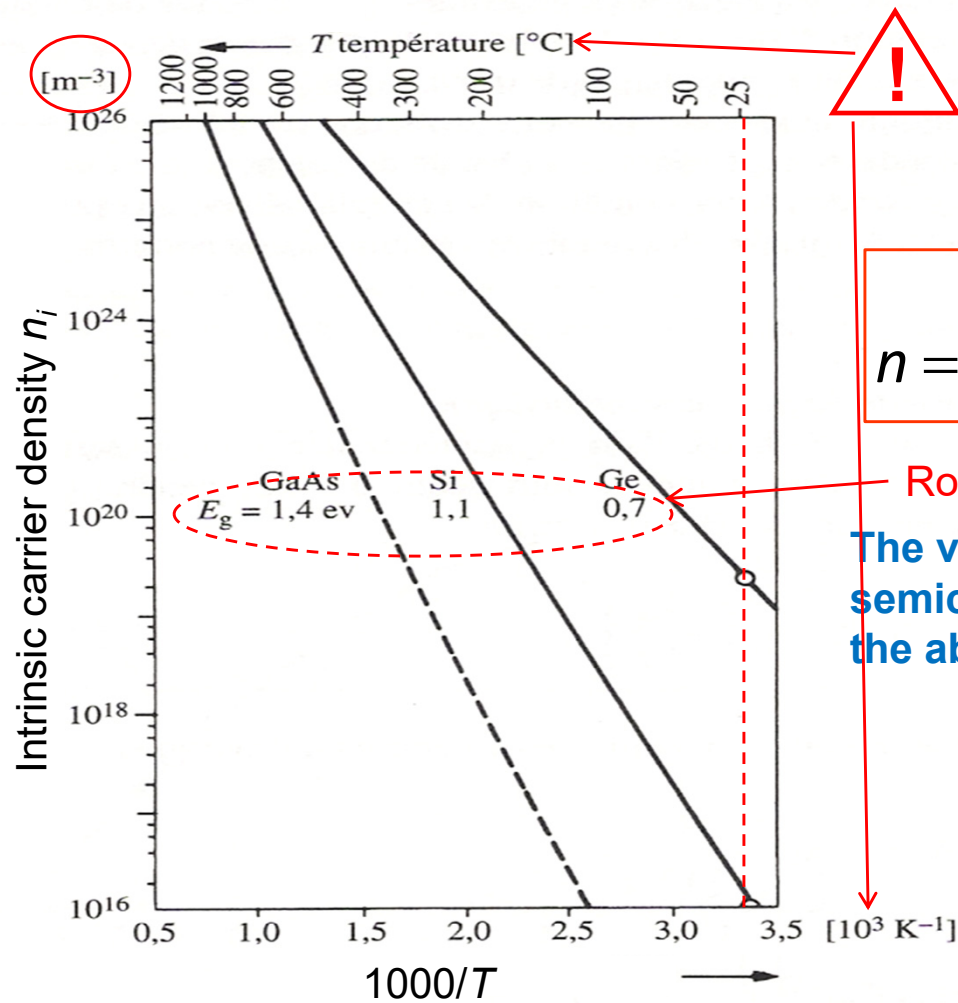
The condition for electrical neutrality throughout the crystal leads to  $n = p = n_i$  at equilibrium, so that:

intrinsic

$$np = n_i^2 = N_c N_v e^{-\frac{E_c - E_v}{k_B T}} = N_c N_v e^{-\frac{E_g}{k_B T}}$$

$$n = p = n_i = \sqrt{N_c N_v} e^{-\frac{E_g}{2k_B T}}$$

# Intrinsic semiconductors



$$n = p = n_i = \sqrt{N_c N_v} e^{-\frac{E_g}{2k_B T}}$$

Room temperature bandgap!

The value of  $n_i$  will set the sensitivity of a given semiconductor to residual impurities and hence the ability to precisely control  $n$ - and  $p$ -type doping

# Intrinsic semiconductors

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## Fermi level position in an intrinsic semiconductor

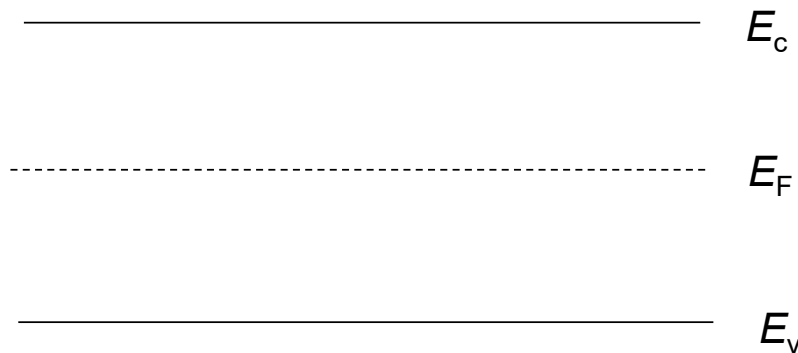
$$n = N_c e^{(E_F - E_c)/k_B T}$$

$$p = N_v e^{(E_v - E_F)/k_B T}$$

$$E_F = E_c - k_B T \ln \frac{N_c}{n} = E_v + k_B T \ln \frac{N_v}{p}$$

$$E_F = \left( \frac{E_v + E_c}{2} \right) + \frac{k_B T}{2} \ln \left( \frac{N_v}{N_c} \right)$$

$N_v$  and  $N_c$  are comparable therefore  **$E_F$  is close to the mid-gap** (cf. slide #28, Lecture 5 )





# Semiconductor – degenerate case

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**Degenerate SC  $\Rightarrow$  highly doped**

$$E_F = E_c - k_B T \ln \frac{N_c}{n} \quad \text{with } n > N_c \text{ (case of an } n\text{-type SC)}$$

**The Fermi level lies within the CB  $\Rightarrow$  Boltzmann approximation is no longer valid** (cf. slide #4 and slide #26, Lecture 5)

One may consider as a rough approximation a Heaviside step function to account for the occupancy statistics:

$$\begin{aligned} f(E) &= 1 \text{ when } E < E_F \\ f(E) &= 0 \text{ when } E > E_F \\ n &= \int_{E_c}^{E_F} \rho_c(E) dE = \frac{1}{2\pi^2} \left( \frac{2m^*}{\hbar^2} \right)^{3/2} \int_{E_c}^{E_F} (E - E_c)^{1/2} dE \\ &= \frac{1}{3\pi^2} \left( \frac{2m^*}{\hbar^2} \right)^{3/2} (E_F - E_c)^{3/2} \end{aligned}$$

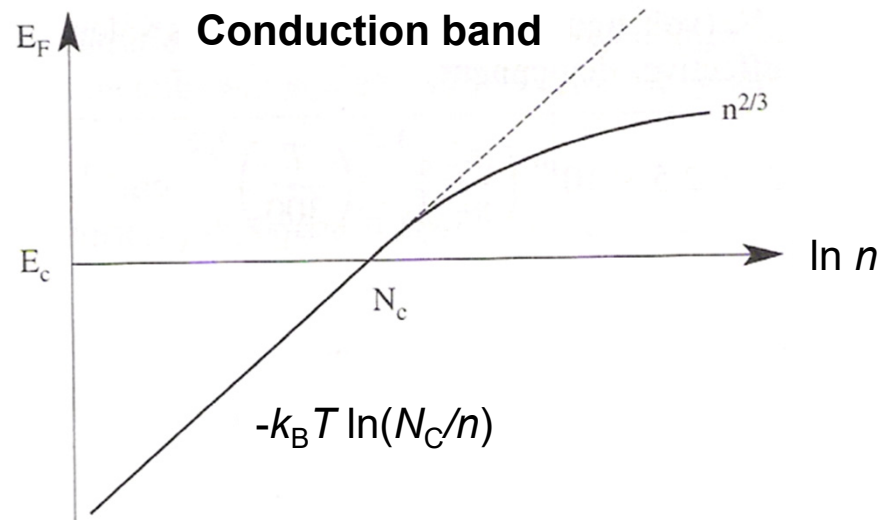
**$n$  is independent of  $T$**

More detailed description to be seen in the exercises !

## Semiconductor – degenerate case

A degenerate SC behaves like a metal (but this is not exactly a metal, why?)

We speak about a semimetallic behavior



For  $n > N_C$ , the Fermi level position varies as  $n^{2/3}$



The  $np = n_i^2$  relationship is not valid anymore in the degenerate case!

# Semiconductor – doped case

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## Occupancy of the donor and acceptor levels

(consideration valid only at low temperature or for deep level states)

$N_D$  (cm<sup>-3</sup>) donor concentration with an ionization energy  $E_D$  (for 1 electron)

$N_D^0$  Concentration of neutral donors

$N_D^+$  Concentration of ionized donors

# Semiconductor – doped case

## Occupancy of the donor (and acceptor) levels

Number of electrons in state  $j$

$$\langle n \rangle = \frac{N_D^0}{N_D} = \frac{\sum_j N_j g_j^{-1} e^{-\beta(E_j - N_j E_F)}}{\sum_j g_j^{-1} e^{-\beta(E_j - N_j E_F)}} = \frac{1}{1 + g_D e^{(E_c - E_D - E_F)/k_B T}}$$

Mean number of  $e^-$  bound to donors

partition function

$g_D^{-1} = 2$  (spin degeneracy factor) and  $\beta = 1/k_B T$   
(only 1 electron due to  $e^-e^-$  interaction)

Thus, the density of ionized donors is

$$N_D^+ = N_D - N_D^0 = N_D \frac{1}{1 + 2e^{(E_F - E_c + E_D)/k_B T}}$$

$$1 - \frac{1}{1 + Ae^\alpha} = \frac{1}{1 + 1/Ae^{-\alpha}}$$

What happens when:

- $T$  increases ?
- $E_D$  increases ?

$\Rightarrow$  To be seen in the exercises !  
Very important concept



# Charge neutrality condition

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The charge neutrality condition within the crystal implies that positive and negative charges compensate themselves

$$n + N_A^- = p + N_D^+$$

Charge neutrality condition  $\Rightarrow$  the Fermi level is fixed at a given  $T$

**Assumption:** donors and acceptors are fully ionized at 300 K:

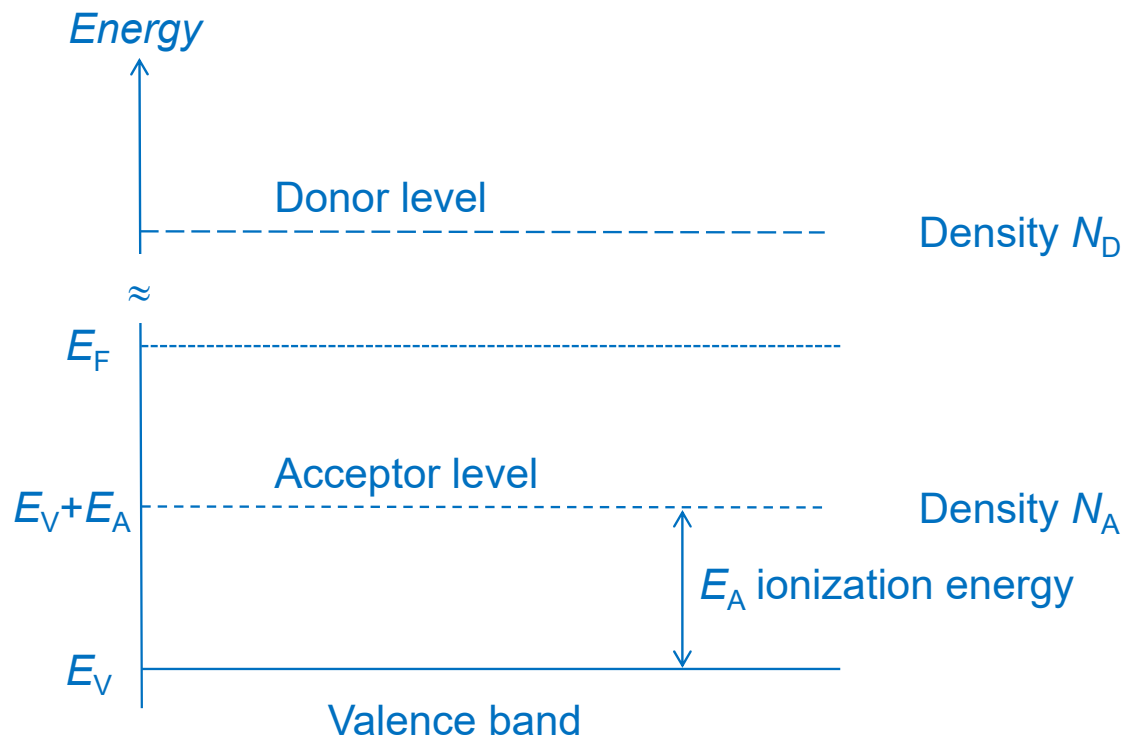
$$n + N_A = p + N_D$$



Always use the appropriate approximation to derive  $n$ ,  $p$ ,  $N_A$  and  $N_D$ !  
The sign of  $N_A$  and  $N_D$  will also depend on the experimental situation.

# Charge neutrality condition: an illustrative example

Diagrammatic example: case of a partially compensated  $p$ -type doped sample



$$p + N_D = N_A^-$$

$$p = N_V \exp\left(\frac{E_V - E_F}{k_B T}\right)$$

$$N_A^- = N_A f_A = N_A \left[ 1 + g_A \exp\left(\frac{E_V + E_A - E_F}{k_B T}\right) \right]^{-1}$$

Spin degeneracy factor

# N-type semiconductor: temperature dependence

$N_D$  donors with an ionization energy  $E_D$  and without acceptors

## Intermediate temperature case:

Donors are fully ionized but no electron coming from the VB

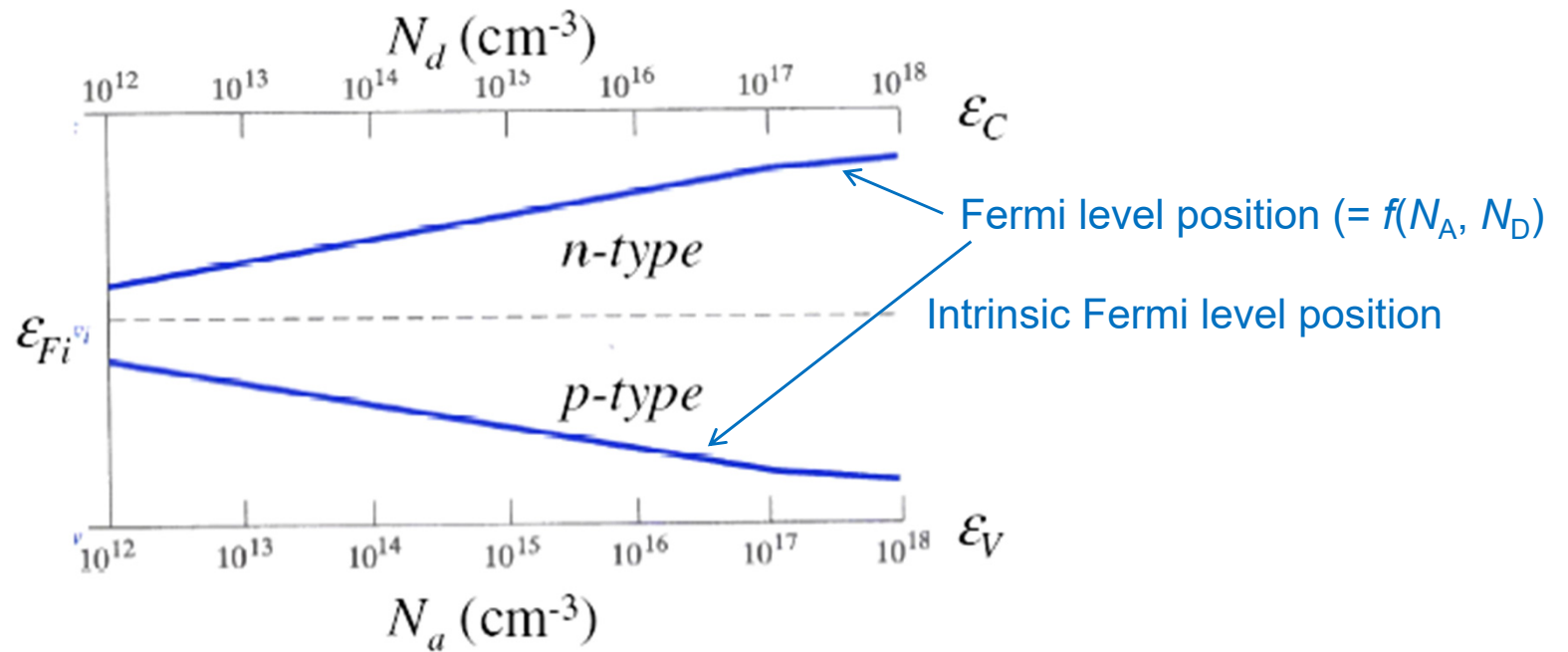
$$(p = 0) \Rightarrow n = N_D$$

*Fermi level position*  $E_F - E_c = k_B T \ln \frac{N_D}{N_c}$

*For a typical doping level of  $10^{17} \text{ cm}^{-3}$  in Si and at 300 K,  $E_F - E_c \approx -145 \text{ meV}$*

*The Fermi energy is below the donor state level*    Whose position is given by?

# Fermi level energy vs doping





# N-type semiconductor: temperature dependence

Above a certain temperature, intrinsic ionization is no longer negligible.

Thus, the charge neutrality condition will write as follows:

$$n = N_D + p$$

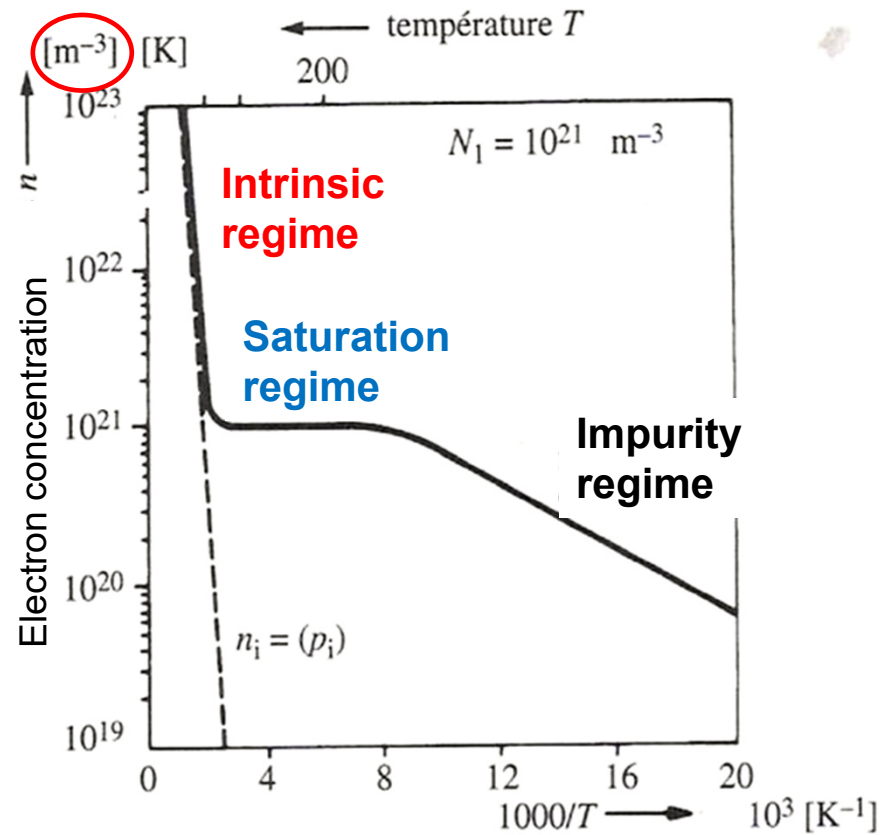
*n* can be expressed as a function of  $n_i$  and  $N_D$ :

$$np = n_i^2 \longrightarrow n = \frac{1}{2}N_D + \left( \frac{N_D^2}{4} + n_i^2 \right)^{1/2} \quad \text{Cf. slides \# 5 \& 6}$$

For the intermediate temperature range ( $n_i \ll N_D$ )

$$n \approx N_D + \frac{n_i^2}{N_D} \approx N_D \quad \text{and} \quad p \approx \frac{n_i^2}{N_D} \quad \text{Saturation regime}$$

# N-type semiconductor: temperature dependence



# N-type semiconductor: temperature dependence

- **Saturation regime:**  $n \approx N_D$
- The concentration of holes is much lower than that of electrons
  - Electrons are called **majority carriers**
  - Holes are called **minority carriers**
- **The conductivity only depends on the donor concentration:**  
 **$\Rightarrow$  extrinsic conductivity ( $\sigma = ne\mu$ )**  
 Mobility (to be defined)!

# Doped semiconductor: temperature dependence

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## 1. High temperature range (intrinsic properties)

$n_i$  much larger than  $N_D$  and  $N_A$

$\Rightarrow$  the charge neutrality condition is simply equal to  $n = p = n_i$

## 2. Intermediate temperature range (extrinsic properties)

Donors and acceptors are fully ionized

$n \approx N_D - N_A \approx \text{constant}$  ( $n$ -type doping)

and  $p \approx N_A - N_D \approx \text{constant}$  ( $p$ -type doping)

## 3. Low temperature range (condensation/impurity regime)

Partial impurity ionization

$\Rightarrow$  the charge neutrality condition is equal to  $n + N_A^- = p + N_D^+$

# Doped semiconductor

## Charges

| Symbol  | Nature                         | Charge |
|---------|--------------------------------|--------|
| $N_A^0$ | Neutral acceptor concentration | 0      |
| $N_A^-$ | Ionized acceptor concentration | -e     |
| $N_D^0$ | Neutral donor concentration    | 0      |
| $N_D^+$ | Ionized donor concentration    | +e     |
| $n$     | Free electron concentration    | -e     |
| $p$     | Free hole concentration        | +e     |

## Charge neutrality condition

$$n + N_A^- = p + N_D^+$$

Very important concept



**Donors and acceptors are fully ionized at 300 K:**

$$N_A^- = N_A \quad N_D^+ = N_D$$

$$n + N_A = p + N_D$$

*Nota bene:* When a semiconductor contains both donors and acceptors, it can be said to be compensated because, under equilibrium conditions, some of the electrons from the donors will be captured (or compensated) by the acceptors ( $\Rightarrow$  a compensated sample contains both ionized donors ( $D^+$ ) and acceptors ( $A^-$ )).

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# Carrier transport

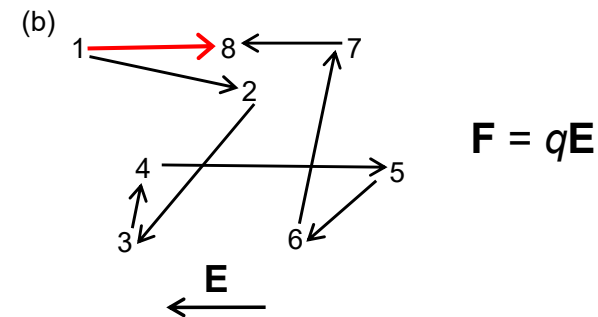
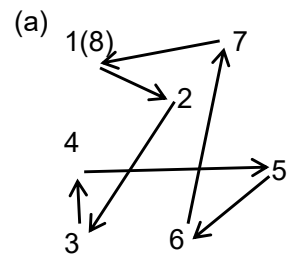
# Thermal equilibrium

## Thermal scattering

### Origins:

- atoms
- ionized impurities
- defects
- other electrons

**Isotropic scattering processes**  $\Rightarrow$  the net charge displacement is equal to zero



**No longer the case when an electric field is applied (symmetry breaking)**

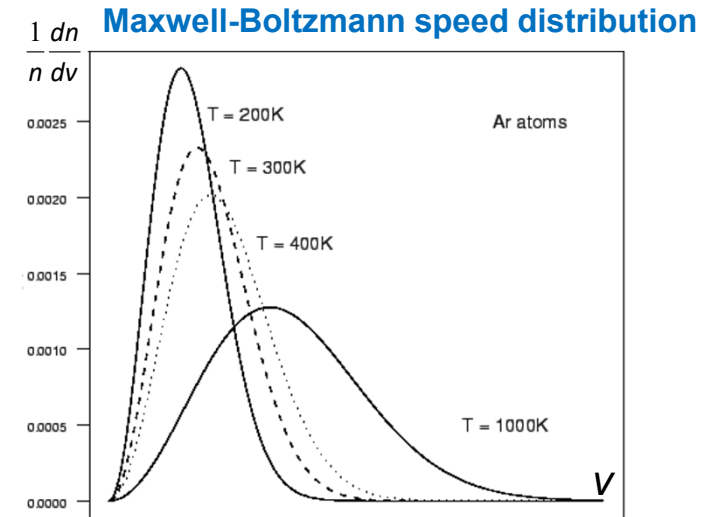
# Thermal equilibrium

## Nearly-free electrons $\Rightarrow$ molecules in a gas

### Maxwell-Boltzmann distribution law:

For an electron gas with  $n$  electrons per unit volume, the number of electrons with a velocity ranging between  $v$  and  $v+dv$  is given by:

$$dn = 4\pi v^2 n \left( \frac{m^*}{2\pi k_B T} \right)^{3/2} e^{-(m^* v^2 / 2k_B T)} dv$$



The **root-mean-square speed** is related to temperature through

$$\frac{1}{2} m^* v_{\text{th}}^2 = \frac{3}{2} k_B T$$

**Equipartition theorem (in 3D)**  $\Rightarrow$  To be seen in the exercises!

At 300 K, the electron velocity in Si is about  $10^7 \text{ cm s}^{-1}$

The **mean free path**  $\lambda$  is determined by the time between 2 collisions

$\tau_c$  is the *mean-free time*

$$\tau_c = 0.1 - 1 \text{ ps}, \lambda = \tau_c v_{\text{th}} = \mathbf{10 \text{ to } 100 \text{ nm}}$$



# Conductivity with an electric field

**Condition:** moderate electric field

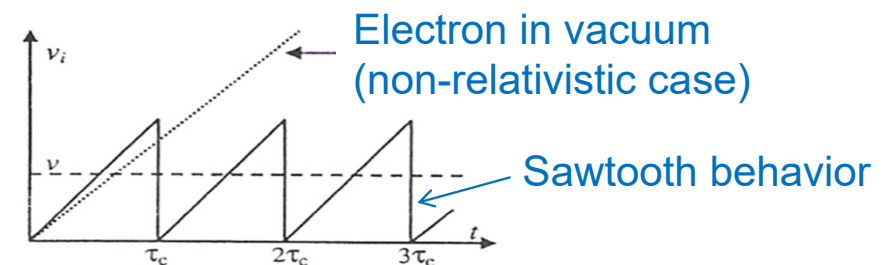
⇒ constant scattering rate, or velocity increase much smaller than  $v_{th}$

**$F = qE$  is the force induced by the electric field on the carriers**

$$F = qE = m^* \frac{dv_i(t)}{dt} \quad v_i \text{ carrier velocity along the electric field}$$

After integration between  $t_0$  and  $t_0+t$ :

$$v_i(t) = q \frac{E}{m^*} t$$



# Conductivity with an electric field

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## Drude model:

The average scattering time (*mean-free time*)  $\tau_c$  is given by

$$\langle t \rangle = \int_0^\infty t P(t) dt = \tau_c$$

Scattering probability per unit time

The average velocity is then equal to:

$$\langle v \rangle = q \frac{\langle t \rangle}{m^*} E = \frac{q \tau_c}{m^*} E$$

$$\langle v \rangle = v_d = \mu E \quad \text{with} \quad \mu = \frac{q \tau_c}{m^*} \quad \text{v}_d \text{ is the drift velocity}$$

$v_d$  is proportional to the electric field (Ohm's law)

$\mu$  is the **mobility**

# Conductivity with an electric field

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$$\mu = \frac{q \tau_c}{m^*}$$

- The mobility determines the performance of (opto)electronic devices
- It depends on the scattering rate and effective mass
- Units:  $\text{cm}^2 \text{V}^{-1} \text{s}^{-1}$